

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
P-3454-USAPPLICATION NO.
10/023,469INFORMATION DISCLOSURE
STATEMENT BY APPLICANTAPPLICANT
Boaz EitanCONFIRMATION NO.
3554FILING DATE
12/20/01GROUP
2818

U.S. PATENT DOCUMENTS

| EXAM. INITIAL | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE |
|------------------|--------------------|------------|------------------|-------|----------|-------------------------------|
| W | 3,895,360 | 07/15/1975 | Cricchi et al. | | | |
| W | 4,016,588 | 04/05/1977 | Ohya et al. | | | |
| | 4,017,888 | 04/12/1977 | Christie et al. | | | |
| | 4,151,021 | 04/24/1979 | McElroy | | | |
| | 4,173,766 | 11/06/1979 | Hayes | | | |
| | 4,173,791 | 11/06/1979 | Bell | | | |
| | 4,281,397 | 07/28/1981 | Neal et al. | | | |
| | 4,306,353 | 12/22/1981 | Jacobs et al. | | | |
| | 4,342,149 | 08/3/1982 | Jacobs et al. | | | |
| | 4,360,900 | 11/23/1982 | Bate | | | |
| | 4,380,057 | 04/12/1983 | Kotecha et al. | | | |
| | 4,388,705 | 06/14/1983 | Sheppard | | | |
| | 4,389,705 | 06/21/1983 | Sheppard | | | |
| | 4,471,373 | 09/11/1984 | Shimizu et al. | | | |
| | 4,527,257 | 07/02/1985 | Cricchi | | | |
| | 4,586,163 | 04/29/1986 | Koike | | | |
| | 4,630,085 | 12/16/1986 | Koyama | | | |
| | 4,667,217 | 05/19/1987 | Janning | | | |
| | 4,742,491 | 05/03/1988 | Liang et al. | | | |
| | 4,780,424 | 10/25/1988 | Holler et al. | | | |
| | 4,847,808 | 07/11/1989 | Kobatake | | | |
| | 4,870,470 | 09/26/1989 | Bass, Jr. et al. | | | |
| | 4,916,671 | 04/10/1990 | Ichiguchi | | | |
| | 4,941,028 | 07/10/1990 | Chen et al. | | | |
| | 5,021,999 | 06/4/1991 | Kohda et al. | | | |
| | 5,075,245 | 12/24/1991 | Woo et al. | | | |
| W | 5,117,389 | 05/26/1992 | Yiu | | | |
| W | 5,168,334 | 12/1/1992 | Mitchell et al. | | | |
| W | 5,172,338 | 12/15/1992 | Mehrotra et al. | | | |
| W | 5,175,120 | 12/29/1992 | Lee | | | |

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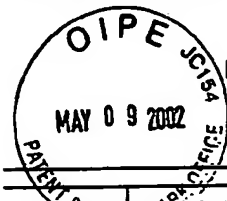
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|---------------------|--------------------|------------|---------------------|-------|----------|-------------------------------|
| W | 5,214,303 | 05/25/1993 | Aoki | | | |
| W | 5,241,497 | 08/31/1993 | Komarek | | | |
| | 5,260,593 | 11/9/1993 | Lee | | | |
| | 5,268,861 | 12/07/1993 | Hotta | | | |
| | 5,289,412 | 02/22/1994 | Frary et al. | | | |
| | 5,293,563 | 03/8/1994 | Ohta | | | |
| | 5,305,262 | 04/19/1994 | Yoneda | | | |
| | 5,311,049 | 05/10/1994 | Tsuruta | | | |
| | 5,315,541 | 05/24/1994 | Harari et al. | | | |
| | 5,338,954 | 08/16/1994 | Shimoji | | | |
| | 5,345,425 | 09/6/1994 | Shikatani | | | |
| | 5,349,221 | 09/20/1994 | Shimoji | | | |
| | 5,350,710 | 09/27/1994 | Hong et al. | | | |
| | 5,359,554 | 10/25/1994 | Odake et al. | | | |
| | 5,375,094 | 12/20/1994 | Naruke | | | |
| | 5,393,701 | 02/28/1995 | Ko et al. | | | |
| | 5,394,355 | 2/28/1995 | Uramoto et al. | | | |
| | 5,399,891 | 03/21/1995 | Yiu et al. | | | |
| | 5,412,601 | 05/02/1995 | Sawada et al. | | | |
| | 5,414,693 | 05/09/1995 | Ma et al. | | | |
| | 5,418,176 | 5/23/1995 | Yang et al. | | | |
| | 5,418,743 | 5/23/1995 | Tomioka et al. | | | |
| | 5,422,844 | 06/06/1995 | Wolstenholme et al. | | | |
| | 5,424,978 | 06/13/1995 | Wada et al. | | | |
| | 5,426,605 | 06/20/1995 | Van Berkel et al. | | | |
| | 5,434,825 | 07/18/1995 | Harari | | | |
| W | 5,450,341 | 09/12/1995 | Sawada et al. | | | |
| W | 5,450,354 | 09/12/1995 | Sawada et al. | | | |
| W | 5,467,308 | 11/14/1995 | Chang et al. | | | |
| W | 5,477,499 | 12/19/1995 | Van Buskirk et al. | | | |

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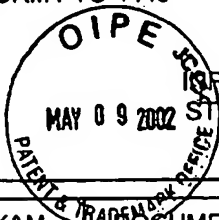
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|------------------|--------------------|------------|---------------------------|-------|----------|-------------------------------|
| W | 5,495,440 | 02/27/1996 | Asakura | | | |
| W | 5,521,870 | 05/28/1996 | Ishikawa | | | |
| | 5,523,251 | 06/04/1996 | Hong | | | |
| | 5,553,018 | 09/03/1996 | Wang et al. | | | |
| | 5,583,808 | 12/10/1996 | Brahmbhatt | | | |
| | 5,599,727 | 02/04/1997 | Hakozaki et al. | | | |
| | 5,623,438 | 04/22/1997 | Guritz et al. | | | |
| | 5,654,568 | 08/05/1997 | Nakao | | | |
| | 5,656,513 | 08/12/1997 | Wang et al. | | | |
| | 5,661,060 | 08/26/1997 | Gill et al. | | | |
| | 5,683,925 | 11/04/1997 | Irani et al. | | | |
| | 5,712,814 | 01/27/1998 | Fratin et al. | | | |
| | 5,726,946 | 03/10/1998 | Yamagata et al. | | | |
| | 5,751,037 | 05/12/1998 | Aozasa et al. | | | |
| | 5,754,475 | 05/19/1998 | Bill et al. | | | |
| | 5,768,192 | 06/16/1998 | Eitan | | | |
| | 5,777,919 | 07/07/1998 | Chi-Yung et al. | | | |
| | 5,787,036 | 07/28/1998 | Okazawa | | | |
| | 5,793,079 | 08/11/1998 | Georgescu et al. | | | |
| | 5,825,686 | 10/20/1998 | Schmitt-Landsiedel et al. | | | |
| | 5,834,851 | 11/10/1998 | Ikeda et al. | | | |
| | 5,836,772 | 11/17/1998 | Chang et al. | | | |
| | 5,841,700 | 11/24/1998 | Chang | | | |
| | 5,847,441 | 12/8/1998 | Cutter et al. | | | |
| | 5,862,076 | 01/19/1999 | Eitan | | | |
| W | 5,864,164 | 01/26/1999 | Wen | | | |
| W | 5,870,335 | 02/09/1999 | Khan et al. | | | |
| W | 5,946,558 | 08/31/1999 | Hsu | | | |
| W | 5,949,728 | 09/07/1999 | Liu et al. | | | |
| W | 5,963,412 | 10/05/1999 | En | | | |

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|------------------|-----------------|------------|----------------------|-------|----------|----------------------------|
| ✓ | 5,963,465 | 10/05/1999 | Eitan | | | |
| ✓ | 5,973,373 | 10/26/1999 | Krauschneider et al. | | | |
| | 5,990,526 | 11/23/1999 | Bez et al. | | | |
| | 5,991,202 | 11/23/1999 | Derhacopian et al. | | | |
| | 6,011,725 | 01/04/2000 | Eitan | | | |
| | 6,018,186 | 01/25/2000 | Hsu | | | |
| | 6,020,241 | 02/01/2000 | You et al. | | | |
| | 6,028,324 | 02/22/2000 | Su et al. | | | |
| | 6,030,871 | 02/29/2000 | Eitan | | | |
| | 6,034,403 | 03/07/2000 | Wu | | | |
| | 6,063,666 | 05/16/2000 | Chang et al. | | | |
| | 6,081,456 | 06/27/2000 | Dadashev | | | |
| | 6,128,226 | 10/3/2000 | Eitan et al. | | | |
| | 6,134,156 | 10/17/2000 | Eitan | | | |
| | 6,137,718 | 10/24/2000 | Reisinger | | | |
| | 6,163,048 | 12/19/2000 | Hirose et al. | | | |
| | 6,201,282 | 03/13/2001 | Eitan | | | |
| | 08/902,890 | 07/30/1997 | Eitan | | | |
| | 08/905,286 | 07/30/1997 | Eitan | | | |
| | 09/211,981 | 12/14/1998 | Eitan | | | |
| ✓ | 09/348,720 | 07/06/1999 | Eitan | | | |
| ✓ | 09/413,408 | 10/06/1999 | Eitan | | | |
| ✓ | 09/536,125 | 03/28/2000 | Eitan et al. | | | |
| ✓ | 09/761,818 | 01/18/2001 | Eliyahu et al. | | | |

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FOREIGN PATENT DOCUMENTS

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|---------------------|-----------------|------------|---------|-------|----------|-------------|----|
| | | | | | | YES | NO |
| W | EP 0693781 | 01/24/1996 | | | | | |
| W | EP 0751560 | 01/02/1997 | | | | | |
| W | EP 1073120 | 01/31/2001 | | | | | |
| | GB 2157489 | 10/23/1985 | | | | | |
| | JP 09162314 | 06/20/1997 | | | | | |
| | JP 404226071 | 08/14/1992 | | | | | |
| | JP 04291962 | 10/16/1992 | | | | | |
| | JP 05021758 | 01/29/1993 | | | | | |
| | JP 07193151 | 07/28/1995 | | | | | |
| W | WO 96/15553 | 05/23/1996 | | | | | |
| W | WO 99/31670 | 06/24/1999 | | | | | |

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V. N. B. Eitan

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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

| EXAMINER INITIAL | |
|---------------------|--------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| UN | Ricco, Bruno et al., "Nonvolatile Multilevel Memories for Digital Applications," <u>IEEE</u> , Vol. 86, No 12, pages 2399-2421, December, 1998. |
| UN | "2 Bit/Cell EEPROM Cell Using Band-To-Band Tunneling For Data Read-Out," <u>IBM Technical Disclosure Bulletin</u> , U.S. IBM Corp. NY Vol. 35, No. 4B, ISSN:0018-8689, pp. 136-140, September, 1992. |
| UN | Tseng, Hsing-Huang et al., "Thin CVD Stacked Gate Dielectric for ULSI Technology", <u>IEEE</u> , 0-7803-1450-6, pp. 321-324, 1993. |
| UN | Pickar, K.A., "Ion Implantation in Silicon," <u>Applied Solid State Science</u> , Vol. 5, R. Wolfe Edition, Academic Press, New York, pp. 151-249, 1975. |
| UN | Bhattacharyya et al., "FET Gate Structure for Nonvolatile N-Channel Read-Mostly Memory Device," <u>IBM Technical Disclosure Bulletin</u> , U.S. IBM Corp. Volume 18, No. 6, page 1768, November, 1975. |
| UN | Bude et al., "EEPROM/Flash Sub 3.0 V Drain-Source Bias Hot carrier Writing", <u>IEDM</u> 95, pp. 989-992. |
| UN | Bude et al., "Secondary Electron Flash - a High Performance, Low Power Flash Technology for 0.35 um and Below", <u>IEDM</u> 97, pp. 279-282. |
| UN | Bude et al., "Modeling Nonequilibrium Hot Carrier Device Effects", <u>Conference of Insulator Specialists of Europe</u> , Sweden, June, 1997. |
| UN | |

EXAMINER

V. Narayan

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